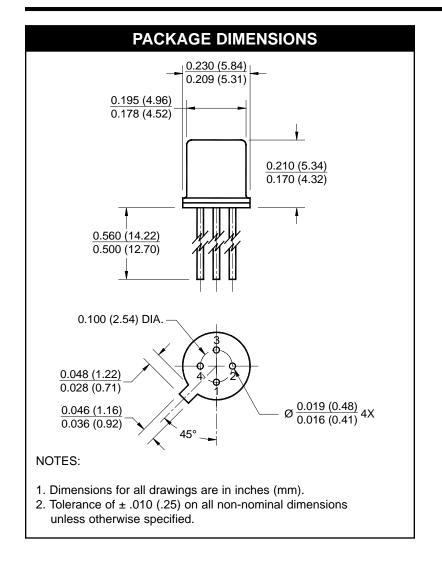
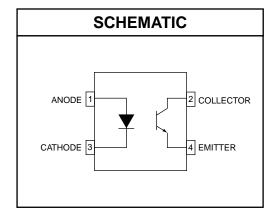
### MCT4







#### **DESCRIPTION**

The MCT4 is a standard four-lead, TO-18 package containing a GaAs infrared emitting diode optically coupled to an NPN silicon planar phototransistor.

#### **FEATURES**

- Hermetically package
- High current transfer ratio; typically 35%
- High isolation resistance; 10<sup>11</sup> ohms at 500 volts
- · High voltage isolation emitter to detector



## MCT4

Parameter	Symbol Rating		Unit	
Operating Temperature	Topr	-55 to +125	°C	
Storage Temperature	T <sub>STG</sub>	-65 to +150	°C	
Soldering Temperature (Flow)	T <sub>SOL-F</sub>	260 for 10 sec	°C	
EMITTER	5			
Power Dissipation at 25°C Ambient (1)	$P_{D}$	90	mW	
Continuous Forward Current	I <sub>F</sub>	40	mA	
Reverse Voltage	V <sub>R</sub>	3	V	
Forward Current - Peak (1 µs pulse, 300 pps)	I <sub>F</sub> (pk)	3.0	Α	
DETECTOR				
Power Dissipation 25°C Ambient (2)	$P_{D}$	200	mW	
Collector to Emitter Voltage	$V_{CEO}$	30	V	
Emitter to Collector Voltage	V <sub>ECO</sub>	7	V	
COUPLER	_			
Total Power Dissipation (3)	$P_{D}$	250	mW	
Isolation Voltage		1000	VDC	

ELECTRICAL / OPTICAL CHARACTERISTICS (T <sub>A</sub> =25	°C)
INDIVIDUAL COMPONENT CHARACTERISTICS	

### INDIVIDUAL COMPONENT CHARACTERISTICS

Parameters	Test Conditions	Symbol	Min	Тур	Max	Units
EMITTER	1 10 A	.,		4.00	4.50	.,,
Forward Voltage	I <sub>F</sub> = 40 mA	V <sub>F</sub>		1.30	1.50	V
Reverse Current	V <sub>R</sub> = 3.0 V	I <sub>R</sub>		0.15	10	μA
Capacitance	V = 0 V	С		150		pF
DETECTOR						
Breakdown Voltage		D./	00			.,
Collector to Emitter	$I_C = 1.0 \text{ mA}, I_F = 0$	BV <sub>CEO</sub>	30			V
Emitter to Collector	$I_E = 100  \mu A,  I_F = 0$	BV <sub>ECO</sub>	7	12		V
Leakage Current	.,			_		
Collector to Emitter	$V_{CE} = 10 \text{ V}, I_{F} = 0$	ICEO		5	50	nA
Capacitance						<u>.</u> .
Collector to Emitter	V <sub>CE</sub> = 0	C <sub>CE</sub>		2		pF

#### NOTE:

- 1. Derate power linearly 1.2 mW/°C above 25°C
- 2. Derate power linearly 2.67 mW/°C above 25°C
- 3. Derate power linearly 3.3 mW/°C above 25°C



## MCT4

TRANSFER CHARACTERISTICS (T <sub>A</sub> = 25°C Unless otherwise specified.)							
DC Characteristics	Test Conditions	Symbol	Min	Тур	Max	Units	
COUPLED		OTD	4.5	0.5		0.4	
DC current Transfer Ratio (note 1)	$V_{CE} = 10 \text{ V}, I_F = 10 \text{ mA}$	CTR	15	35		%	
Saturation Voltage	$I_C = 500 \mu\text{A}, I_F = 10 \text{mA}$	V <sub>CE(SAT)</sub>		0.1		V	
	$I_C = 2 \text{ mA}, I_F = 50 \text{ mA}$			0.2	0.5		
AC Characteristics	Test Conditions	Symbol	Min	Тур	Max	Units	
Capacitance LED to Detector				1.8		pF	
Bandwidth (Fig. 5)	Note 2			300		kHz	
Rise Time and Fall Time (see operating schematic)	$I_C = 2 \text{ mA}, V_{CE} = 10 \text{ V}, \text{ Note } 3$			2		μs	

ISOLATION CHARACTERISTICS						
Characteristic	Test Conditions	Symbol	Min	Тур	Max	Units
Isolation Resistance	V = 500 VDC	R <sub>ISO</sub>	10 <sup>11</sup>	10 <sup>12</sup>		Ω
Breakdown Voltage	Time = 1 sec		1000	1500		VDC

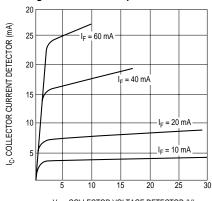
#### NOTE:

- 1. The current transfer ratio ( $I_C/I_F$ ) is the ratio of the detector collector current to the LED input current with  $V_{CE}$  at 10 volts.
- 2. The frequency at which  $i_c$  is 3 dB down from the 1 kHz value.
- 3. Rise time (t<sub>r</sub>) is the time required for the collector current to increase from 10% of its final value, to 90%. Fall time (t<sub>f</sub>) is the time required for the collector current to decrease from 90% of its initial value to 10%.



# MCT4

Figure 1. Detector Output Characteristics



 $V_{\text{CE}}$ , COLLECTOR VOLTAGE DETECTOR (V)

Figure 2. Input Current vs. Output Current

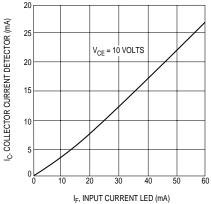


Figure 3. Dark Current vs. Temperature

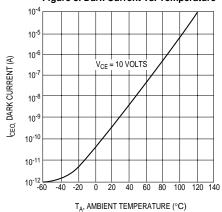


Figure 4. Current Output vs. Temperature

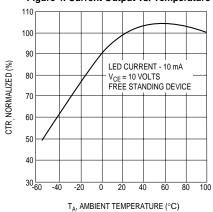


Figure 5. Output vs. Frequency

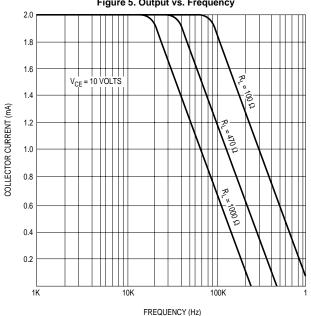
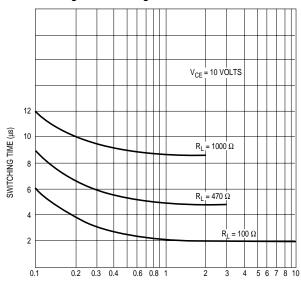


Figure 6. Switching Time vs. Collector Current





# MCT4

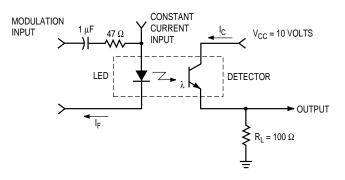


Figure 7. Modulation Circuit Used to Obtain Output vs.
Frequency Plot

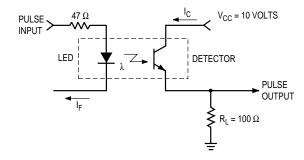


Figure 8. Circuit Used to Obtain Switching Time vs.

Collector Current Plot



MCT4

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